Alignment in Gleam



Leon Rochester Tracy Usher Hiro Tajima SLAC Instrument Analysis Workshop 2 SLAC, September 27, 2004

Goals

- Our original goal was to align each wafer.
 - Hierarchy of volumes: tower, tray, face, ladder, wafer
 - Transformations from higher to lower levels
- Currently, we plan to perform alignment only at the tower level.
 - Obviously needed
 - Indications are that after being characterized, pointing of towers will not move by more than 7 arc-seconds due to temperature variations, so this calibration will be effective.
 - Expect $\pm 50\mu m$ (max) deviations for ladders in trays, perhaps $\pm 100\mu m$ for trays in tower.
 - If necessary, ladder alignment data exist, and tray alignment can be measured independently in each tower using cosmic rays.
- But we will need to monitor the intra-tower residuals anyway
 - Full characterization will still be needed to generate simulated data with realistic internal misalignments, to help us write and test monitoring programs.

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Current Scheme for Constants

- Misalignments of each element are characterized by six constants: three translations (Δx, Δy, Δz) and rotations (α, β, γ) around the three axes.
 - Δx , Δy , and γ are "first-order," that is they produce displacements that don't depend on the track slopes.
 - Δz generates displacements proportional to the track slopes. But since the slopes can be large, these displacements are not necessarily small.
 - α and β generate displacements of both kinds.
- There are two sets of constants, one for simulation and one for reconstruction.



Constants File

- The elements subject to alignment are: Tower, Tray, Face, Ladder, Wafer. Each element in the tracker can be displaced with respect to the one above it in the hierarchy. So:
 - Trays can be displaced with respect to the tower
 - Faces (bottom or top) can be displaced with respect to the tray
 - Ladders can be displaced with respect to the face
 - Wafers can be displaced with respect to the ladder
- As you will see in the example, this scheme allows the description to be as simple or as complex as required by the given task.

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Example Input File

// exam	ple	align	ment	constant	file	for sin	nulatio	n
Tower 3								
11	delta in microns				rot in mrad			
Tray	1	45.	17.	-30	1.5	-0.7	0.3	
Face	1	21	-13	43	0.0	0.5	-1.6	
Face	2	-14	7	-26	0.0	-0.5	1.6	
Tower	4	0	15	-6	0.0	0.0	0.0	
Face	0							
Ladder	1							
Wafer	2	12	-7	24	0.3	-0.5	1.1	
Wafer	1	14	-14	18	0.2	-0.4	1.3	

(If no constants are given, zeros are assumed.)



Setting up Internal Arrays

- This division reflects the way alignment information will be collected in real life. The code reflects this hierarchy.
- At each level
 - Alignment constants at that level, if any, are read in
 - Constants are merged with those from the level above
 - ...including nulls for any not specified
 - The merged constants are passed down to the next level
- At the lowest level (wafers) the constants are inserted into an array containing one entry for each wafer in the detector (...9216 in all for the flight instrument. Treatment is general; two towers is a special case.)

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A Fundamental Choice

Alignment can be introduced by moving the detector or by moving the hit/cluster.



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We move the hits.

- Benefits
 - The geometry (Geant, propagator) can be kept simple. Every element is replicated uniformly.
 - Geometry is nominal, so events don't have to be resimulated every time the alignment is updated.
- Drawbacks
 - Geometry is not quite "correct"
 - Certain pathologies arise during simulation
 - Clusters may not lie on the MC and recon tracks in the display. They show up where they would be if the element were actually displaced.



Procedure

- Simulation
 - For each hit the track is moved according to the constants, and then the resulting track is re-intersected with the active element.
- Reconstruction
 - For each cluster on a track, the nominal position is modified according to the constants and the slopes of the track.
 - Currently, the correction is applied just before fitting.
 - In principle, the first-order corrections could be made when the clusters are constructed, and the remaining corrections could be applied at patrec time. In practice, this would probably be more complicated and confusing.

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Example of Moving a Hit



Here we show the result of moving the silicon plane up, so that the apparent track moves down. Then we re-intersect the track with the silicon plane and calculate new entry and exit points.

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Some Details



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Does it Work?

- In the next six slides, you can see the results of applying the alignment corrections. On each slide, three distributions are overlaid:
 - Vanilla, no alignment applied
 - Alignment corrections applied during simulation
 - Alignment corrections applied during simulation and reconstruction.
- In each slide, the variables plotted are the ones most sensitive to the correction in question.
- The goal is for the first and last distributions to be essentially the same.

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Translation in X



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Translation in Y



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Translation in Z



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Rotation around X Axis





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Rotation around Y Axis



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Rotation around Z Axis



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Areas for improvement

- Reconstruction corrections should probably be applied earlier in the process.
 - Patrec may fail to find a hit on a high-energy track in a misaligned detector.
 - Since the new plan is to make a TkrTrack during patrec, it would seem logical to do the alignment when adding hits.
 - Will slightly increase patrec time... probably not significant
- Simulation: works well in spite of the items below:
 - Hits at the edges of the active areas
 - Interactions in the silicon
 - Nearly horizontal tracks

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Edge Hits



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Interactions in the Silicon



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Lost Interactions



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Nearly Horizontal Tracks





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Constants Finding

(Apologies to Tracy!)

Some History

- Based on the work of Hiro Tajima
 - Standalone ROOT macro
 - Did its own patrec, fitting
 - Geometry put in by hand (now outdated!)
 - Lots of copying of files, hand modifications
- But it seems to have worked!
 - (But couldn't really check, because Leon's stuff wasn't ready...)

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Tracy's Goal

- Integrate with Gleam
- Use as many existing tools as possible
- Break down to functional components to allow exploration of alternative schemes
- Be ready for real data!

How It's Done

- Generate events in misaligned detector, using standard code
 - For this exercise, diagonal high-energy muons
 - To understand what we're doing, we cheat and use MC patrec.
- Perform standard pattern recognition and fitting
- Pick tracks
 - Minimum number of clusters in reference and target tower
- Separate tracks into two parts
 - Reference tower
 - Refit, using only the clusters in that tower
 - Target tower
 - Store measured position and covariance matrix for each hit plane.
 - Replace fit position with extrapolation of reference track.

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How It's Done (2)

- Accumulate events
- Perform minimization (Minuit)
 - Vary parameters in n-dimensional space (n<=6)
 - For each set of parameters, transform measured positions using existing tools
 - Calculate residuals and chi-squared, using weights derived from covariance matrix and measured errors
- Compare results with inputs

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How Are We Doing?

- We have done end-to-end checks of procedure
 - Translation in X
 - Translation in Y
 - Simultaneous translation in X and Y
 - Rotation around X axis
- Original offsets are reproduced!

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Some Diagnostic plots



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More Diagnostic Plots



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What Next?

- Clean up code
- Understand how to interpret errors
- Realistic source spectrum
- Study performance in the presence of internal misalignments
- Exploration of alternate schemes
 - Tracy has one or two in mind



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Where We Stand

- We have checked two-tower alignment end-to-end:
 - Generated events using misaligned tracker
 - Used those events to measure the misalignment
 - Verified that the constants found agree with the input constants
 - Use the constants to correct the fitted tracks.
- We have identified a modest program of improvements to take care of remaining details.
- We await real two-tower data to demonstrate that we are not only consistent, but also correct!